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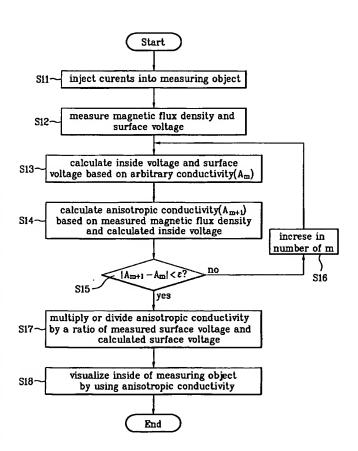
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#### (54) Title: SYSTEM AND METHOD FOR VISUALIZING CONDUCTIVITY AND CURRENT DENSITY DISTRIBUTION IN **OBJECT**



(57) Abstract: System for visualizing conductivity and current density distributions including a plurality of current injecting devices for injecting currents into a measuring object; a measuring unit for measuring a magnetic flux density due to the currents injected into a measuring object; an operating unit for selecting one pair of the current injecting devices in succession so as to inject currents of different directions into the measuring object, and calculating directional components of an anisotropic conductivity inside of the measuring object on the basis of the measured magnetic flux density; and displaying means for visualizing an inside of the measuring object by using the calculated directional components of the anisotropic conductivity.

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